SLAS189A - MARCH 1999 - REVISED JUNE 2000

20 N D1

19 DO

18 TCS

16 LDAC

15 REG

13 OUT

12**∏** REF

11 🛮 V_{DD}

14 ∏ AGND

17 N WE

DW OR PW PACKAGE (TOP VIEW)

D2

D3 **П**

D5 🛮 4

D4 **∏** 3

D6 ∏ 5

D7 🛮 6

D10 🛮 9

D8

D9

D11 [

- 12-Bit Voltage Output DAC
- Programmable Internal Reference
- Programmable Settling Time vs Power Consumption

1 μ s in Fast Mode 3.5 μ s in Slow Mode

- Compatible With TMS320
- Differential Nonlinearity . . . <0.5 LSB Typ
- Voltage Output Range ... 2x the Reference Voltage
- Monotonic Over Temperature

applications

- Digital Servo Control Loops
- Digital Offset and Gain Adjustment
- Industrial Process Control
- Machine and Motion Control Devices
- Mass Storage Devices

description

The TLV5639 is a 12-bit voltage output digital-to-analog converter (DAC) with a microprocessor compatible parallel interface. It is programmed with a 16-bit data word containing 4 control and 12 data bits. Developed for a wide range of supply voltages, the TLV5639 can be operated from 2.7 V to 5.5 V.

The resistor string output voltage is buffered by a x2 gain rail-to-rail output buffer. The buffer features a Class AB output stage to improve stability and reduce settling time. The programmable settling time of the DAC allows the designer to optimize speed versus power dissipation. Because of its ability to source up to 1 mA, the internal reference can also be used as a system reference. With its on-chip programmable precision voltage reference, the TLV5639 simplifies overall system design. The settling time and the reference voltage can be chosen by the control bits within the 16-bit data word.

Implemented with a CMOS process, the device is designed for single supply operation from 2.7 V to 5.5 V. It is available in 20-pin SOIC and TSSOP packages in standard commercial and industrial temperature ranges.

AVAILABLE OPTIONS

	PACK	AGE
TA	SOIC (DW)	TSSOP (PW)
0°C to 70°C	TLV5639CDW	TLV5639CPW
-40°C to 85°C	TLV5639IDW	TLV5639IPW

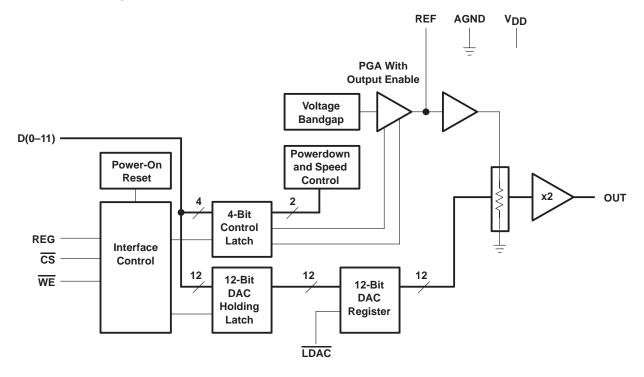


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functional block diagram

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Terminal Functions

TERM	INAL	WO/D	DESCRIPTION
NAME	NO.	I/O/P	DESCRIPTION
AGND	14	Р	Ground
CS	18	I	Chip select. Digital input active low, used to enable/disable inputs
D0 – D11	1 – 10, 19, 20	I	Data input
LDAC	16	I	Load DAC. Digital input active low, used to load DAC output
OUT	13	0	DAC analog voltage output
REG	15	I	Register select. Digital input, used to access control register
REF	12	I/O	Analog reference voltage input/output
V_{DD}	11	Р	Positive power supply
WE	17	I	Write enable. Digital input active low, used to latch data



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absolute maximum ratings over operating free-air temperature range (unless otherwise noted)†

Supply voltage (V _{DD} to AGND)	
Reference input voltage range	
Digital input voltage range	$- 0.3 \text{ V to V}_{DD} + 0.3 \text{ V}$
Operating free-air temperature range, T _A : TLV5639C	0°C to 70°C
TLV5639I	40°C to 85°C
Storage temperature range, T _{stg}	–65°C to 150°C
Lead temperature 1.6 mm (1/16 inch) from case for 10 seconds	260°C

[†] Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

recommended operating conditions

			MIN	NOM	MAX	UNIT
Supply voltage Van	V _{DD} = 5 V		4.5	5	5.5	V
Supply voltage, V _{DD}	V _{DD} = 3 V		2.7	3	3.3	V
Power on threshold voltage, POR			0.55		2	V
High-level digital input voltage, V _{IH}	V _{DD} = 2.7 V to 5.5 V		2			V
Low-level digital input voltage, V _{IL}	V _{DD} = 2.7 V to 5.5 V				0.8	V
Reference voltage, V _{ref} to REF terminal	V _{DD} = 5 V (see Note 1)	A	GND	2.048	V _{DD} -1.5	V
Reference voltage, V _{ref} to REF terminal	V _{DD} = 3 V (see Note 1)	A	GND	1.024	V _{DD} -1.5	V
Load resistance, R _L			2			kΩ
Load capacitance, CL					100	pF
Operating free-air temperature, T _A	TLV5639C		0		70	°C
Operating nee-all temperature, 14	TLV5639I		-40		85	C

NOTE 1: Due to the x2 output buffer, a reference input voltage ≥ V_{DD/2} causes clipping of the transfer function. The output buffer of the internal reference must be disabled, if an external reference is used.



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electrical characteristics over recommended operating free-air temperature range, V_{ref} = 2.048 V, $V_{ref} = 1.024 \text{ V}$ (unless otherwise noted)

power supply

	PARAMETER	TEST CO	TEST CONDITIONS					MAX	UNIT
				REF	Fast		2.3	2.8	mA
IDD		No load, All inputs = AGND or V _{DD} , DAC latch = 0x800	V _{DD} = 5 V	on	Slow		1.3	1.6	mA
				REF off	Fast		1.9	2.4	mA
	Power supply current				Slow		0.9	1.2	mA
			V _{DD} = 3 V	REF	Fast		2.1	2.6	mA
				on	Slow		1.2	1.5	mA
				REF	Fast		1.8	2.3	mA
				off	Slow		0.9	1.1	mA
	Power down supply current						0.01	1	μΑ
PSRR	Dower aupply rejection ratio	Zero scale, See Note 2, External reference					-60		dB
FORK	Power supply rejection ratio	Full scale, See Note 3, External reference					-60		uБ

NOTES: 2. Power supply rejection ratio at zero scale is measured by varying VDD and is given by: $PSRR = 20 log [(E_{ZS}(V_{DD}max) - E_{ZS}(V_{DD}min))/V_{DD}max]$

> 3. Power supply rejection ratio at full scale is measured by varying VDD and is given by: $PSRR = 20 log [(E_G(V_{DD}max) - E_G(V_{DD}min))/V_{DD}max]$

static DAC specifications

	PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
	Resolution			12		bits
INL	Integral nonlinearity, end point adjusted	$R_L = 10 \text{ k}\Omega$, $C_L = 100 \text{ pF}$, See Note 4		±1.2	±3	LSB
DNL	Differential nonlinearity	$R_L = 10 \text{ k}\Omega$, $C_L = 100 \text{ pF}$, See Note 5		±0.3	±0.5	LSB
EZS	Zero-scale error (offset error at zero scale)	See Note 6			±12	LSB
E _{ZS} TC	Zero-scale-error temperature coefficient	See Note 7		20		ppm/°C
EG	Gain error	See Note 8			±0.3	% full scale V
E _G T _C	Gain error temperature coefficient	See Note 9		20		ppm/°C

- NOTES: 4. The relative accuracy or integral nonlinearity (INL) sometimes referred to as linearity error, is the maximum deviation of the output from the line between zero and full scale excluding the effects of zero code and full-scale errors (see text).
 - 5. The differential nonlinearity (DNL) sometimes referred to as differential error, is the difference between the measured and ideal 1 LSB amplitude change of any two adjacent codes. Monotonic means the output voltage changes in the same direction (or remains constant) as a change in the digital input code.
 - 6. Zero-scale error is the deviation from zero voltage output when the digital input code is zero (see text)

 - Zero-scale-error temperature coefficient is given by: EZS TC = [EZS (T_{max}) EZS (T_{min})]/2V_{ref} × 10⁶/(T_{max} T_{min}).
 Gain error is the deviation from the ideal output (2V_{ref} 1 LSB) with an output load of 10 k excluding the effects of the zero-error.
 Gain temperature coefficient is given by: EG TC = [EG(T_{max}) EG (T_{min})]/2V_{ref} × 10⁶/(T_{max} T_{min}).

output specifications

	PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
VO	Output voltage	$R_L = 10 \text{ k}\Omega$			V _{DD} -0.4	V
	Output load regulation accuracy	$V_O = 4.096 \text{ V}, 2.048 \text{ V} R_L = 2 \text{ k}\Omega$			±0.29	% full scale V



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electrical characteristics over recommended operating free-air temperature range, $V_{ref} = 2.048 \text{ V}$, $V_{ref} = 1.024 \text{ V}$ (unless otherwise noted) (Continued)

reference pin configured as output (REF)

	PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
V _{ref} (OUTL)	Low reference voltage		1.003	1.024	1.045	V
V _{ref} (OUTH)	High reference voltage	V _{DD} > 4.75 V	2.027	2.048	2.069	V
I _{ref(source)}	Output source current				1	mA
Iref(sink)	Output sink current		-1			mA
PSRR	Power supply rejection ratio			-48		dB

reference pin configured as input (REF)

	PARAMETER	TEST CONDITIONS	TEST CONDITIONS			TYP	MAX	UNIT	
٧ _I	Input voltage				0		V _{DD-1.5}	V	
Rį	Input resistance					10		ΜΩ	
Cl	Input capacitance					5		pF	
	Deference input handwidth	REF = 0.2 V _{pp} + 1.024 V dc Fast Slow		Fast		900		kHz	
	Reference input bandwidth				500		KHZ		
		40.111-	10 kHz	Fast		-87		dB	
			Slov	Slow		-77		uБ	
1	Harmonic distortion, reference input	REF = 1 V_{pp} + 2.048 V dc, V_{DD} = 5 V	E0 kH=	Fast		-74		dB	
	put		50 kHz	50 KHZ	Slow		-61		uБ
			100 kHz	Fast		-66		dB	
	Reference feedthrough	REF = 1 V _{pp} at 1 kHz + 1.024 V dc (see	REF = 1 V _{pp} at 1 kHz + 1.024 V dc (see Note 10)			-80		dB	

NOTE 10: Reference feedthrough is measured at the DAC output with an input code = 0x000.

digital inputs

	PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
lіН	High-level digital input current	$V_I = V_{DD}$			1	μΑ
I _{IL}	Low-level digital input current	V _I = 0 V	-1			μΑ
Ci	Input capacitance			8		pF



TLV5639C, TLV5639I 2.7-V TO 5.5-V LOW-POWER 12-BIT DIGITAL-TO-ANALOG CONVERTERS WITH INTERNAL REFERENCE AND POWER DOWN SLAS189A - MARCH 1999 - REVISED JUNE 2000

operating characteristics over recommended operating free-air temperature range, $V_{ref} = 2.048 \text{ V}$, and $V_{ref} = 1.024 \text{ V}$, (unless otherwise noted)

analog output dynamic performance

	PARAMETER	TES1	CONDITIONS		MIN	TYP	MAX	UNIT
+>	Output settling time, full scale	$R_L = 10 \text{ k}\Omega$,	C _L = 100 pF,	Fast		1	3	
ts(FS)	Output settiing time, full scale	See Note 11	_	Slow		3.5	7	μs
	Output cettling time, and to and	$R_L = 10 \text{ k}\Omega$, $C_L = 10$ See Note 12	C _L = 100 pF,	Fast		0.5	1.5	
ts(CC)	Output settling time, code to code			Slow		1	2	μs
SR	Slew rate	$R_L = 10 \text{ k}\Omega$,	C _L = 100 pF,	Fast	6	10		\//···
SK	Siew rate	See Note 13		Slow	1.2	1.7		V/μs
	Glitch energy	$\frac{DIN = 0 \text{ to } 1,}{CS = V_{DD}}$	f _{CLK} = 100 kH	z,		5		nV-S
SNR	Signal-to-noise ratio				73	78		
SINAD	Signal-to-noise + distortion	f _S = 480 kSPS,			61	67		dB
THD	Total harmonic distortion	f _B = 20 kHz, C _I = 100 pF	$R_L = 10 \text{ k}\Omega$,			-69	-62	ub
SFDR	Spurious free dynamic range]			63	74		

- NOTES: 11. Settling time is the time for the output signal to remain within ± 0.5 LSB of the final measured value for a digital input code change of 0x020 to 0xFDF or 0xFDF to 0x020.
 - 12. Settling time is the time for the output signal to remain within \pm 0.5 LSB of the final measured value for a digital input code change of one count.
 - 13. Slew rate determines the time it takes for a change of the DAC output from 10% to 90% full-scale voltage.

digital input timing requirements

		MIN	NOM	MAX	UNIT
t _{su(CS-WE)}	Setup time, CS low before negative WE edge	15			ns
t _{su(D)}	Setup time, data ready before positive WE edge	10			ns
t _{su(R)}	Setup time, REG ready before positive WE edge	20			ns
th(DR)	Hold time, data and REG held valid after positive WE edge	5			ns
tsu(WE-LD)	Setup time, positive WE edge before LDAC low	5			ns
twH(WE)	Pulse duration, WE high	20			ns
t _{w(LD)}	Pulse duration, LDAC low	23			ns



PARAMETER MEASUREMENT INFORMATION

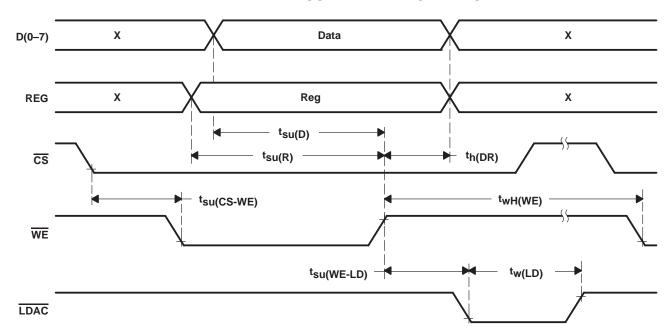


Figure 1. Timing Diagram

TYPICAL CHARACTERISTICS

DIFFERENTIAL NONLINEARITY ERROR DNL - Differential Nonlinearity - LSB 0.8 0.6 0.4 0.2 0 -0.2 -0.4 -0.6 -0.8 0 512 1024 1536 2048 2560 3072 3584 4096 **Digital Code**

Figure 2

INTEGRAL NONLINEARITY ERROR

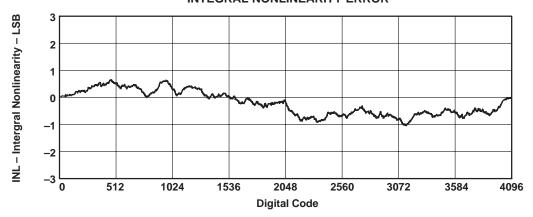
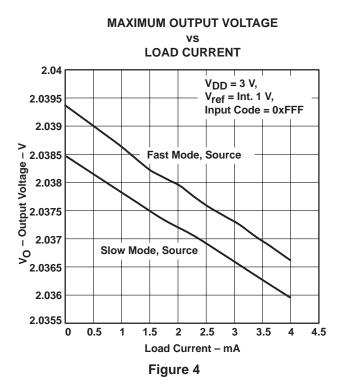


Figure 3



TYPICAL CHARACTERISTICS



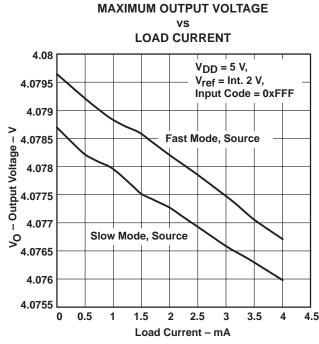
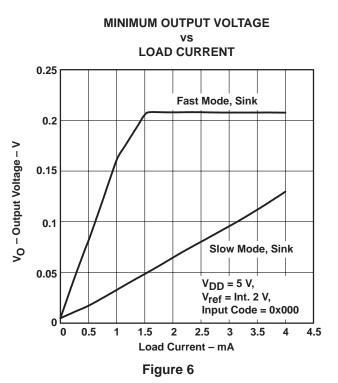
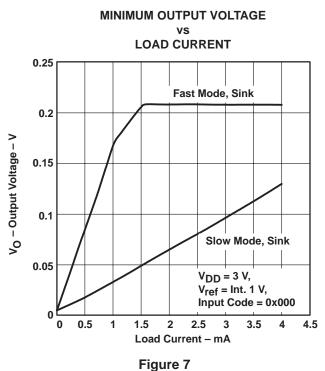


Figure 5





TYPICAL CHARACTERISTICS

TOTAL HARMONIC DISTORTION TOTAL HARMONIC DISTORTION AND NOISE **FREQUENCY FREQUENCY** THD+N - Total Harmonic Distortion and Noise - dB $V_{DD} = 5 V$, $V_{DD} = 5 V$, REF = 1 V dc + 1 V pp Sinewave, REF = 1 V dc + 1 V pp Sinewave, -10THD - Total Harmonic Distortion - dB **Output Full Scale Output Full Scale** -20 -20-30 -30-40 -40 -50 -50 -60 -60 Slow Mode -70 Slow Mode -70 -80 -80 **Fast Mode Fast Mode** -90 -90 -100-100 10000 100000 1000 100 100 1000 10000 100000 f - Frequency - Hz f - Frequency - Hz Figure 8 Figure 9

POWER DOWN SUPPLY CURRENT

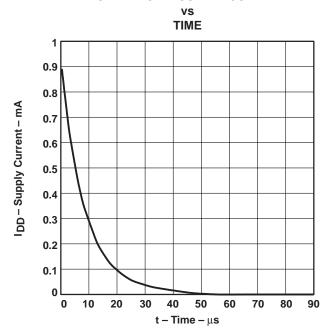


Figure 10



APPLICATION INFORMATION

general function

The TLV5639 is a 12-bit, single supply DAC, based on a resistor string architecture. It consists of a parallel interface, a speed and power down control logic, a programmable internal reference, a resistor string, and a rail-to-rail output buffer. The output voltage (full scale determined by reference) is given by:

2 REF
$$\frac{\text{CODE}}{0\text{x}1000}$$
 [V]

Where REF is the reference voltage and CODE is the digital input value in the range 0x000 to 0xFFF. A power-on reset initially puts the internal latches to a defined state (all bits zero).

parallel interface

The device latches data on the positive edge of $\overline{\text{WE}}$. It must be enabled with $\overline{\text{CS}}$ low. Whether the data is written to the DAC holding latch or the control register depends on REG. REG = 0 selects the DAC holding latch, REG = 1 selects the control register. $\overline{\text{LDAC}}$ low updates the DAC with the value in the holding latch. $\overline{\text{LDAC}}$ is an asynchronous input and can be held low, if a separate update is not necessary. However, to control the DAC using the load feature, there should be approximately a 5 ns delay after the positive $\overline{\text{WE}}$ edge before driving $\overline{\text{LDAC}}$ low.

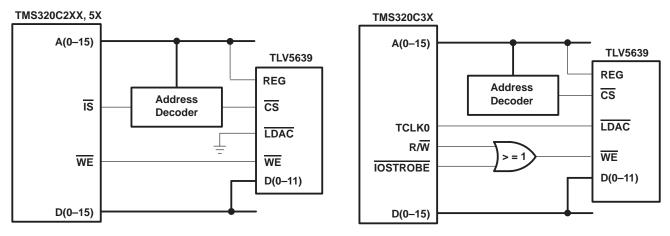


Figure 11

data format

The TLV5639 writes data either to the DAC holding latch or to the control register, depending on the level of the REG input.

Data destination:

REG = $0 \rightarrow DAC$ holding latch REG = $1 \rightarrow control$ register



APPLICATION INFORMATION

The following table lists the meaning of the bits within the control register:

D11	D10	D9	D8	D7	D6	D5	D4	D3	D2	D1	D0
Х	Х	Х	Х	Х	Х	Х	REF1	REF0	Х	PWR	SPD
χţ	χt	χţ	χt	χ†	χt	χt	0†	0†	χt	0†	0†

[†] Default values

X: don't care

SPD: Speed control bit $1 \rightarrow \text{fast mode}$ $0 \rightarrow \text{slow mode}$ PWR: Power control bit $1 \rightarrow \text{power down}$ $0 \rightarrow \text{normal operation}$

REF1 and REF0 determine the reference source and the reference voltage.

REFERENCE BITS

REF1	REF0	REFERENCE		
0	0	External		
0	1	1.024 V		
1	0	2.048 V		
1	1	External		

If an external reference voltage is applied to the REF pin, external reference must be selected.

linearity, offset, and gain error using single end supplies

When an amplifier is operated from a single supply, the voltage offset can still be either positive or negative. With a positive offset, the output voltage changes on the first code change. With a negative offset the output voltage may not change with the first code depending on the magnitude of the offset voltage.

The output amplifier attempts to drive the output to a negative voltage. However, because the most negative supply rail is ground, the output cannot drive below ground and clamps the output at 0 V.

The output voltage remains at zero until the input code value produces a sufficient positive output voltage to overcome the negative offset voltage, resulting in the transfer function shown in Figure 12.

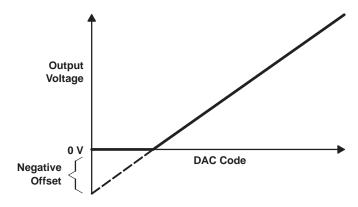


Figure 12. Effect of Negative Offset (Single Supply)

This offset error, not the linearity error, produces this breakpoint. The transfer function would have followed the dotted line if the output buffer could drive below the ground rail.

For a DAC, linearity is measured between zero input code (all inputs 0) and full scale code (all inputs 1) after offset and full scale are adjusted out or accounted for in some way. However, single supply operation does not allow for adjustment when the offset is negative due to the breakpoint in the transfer function. So the linearity is measured between full scale code and the lowest code that produces a positive output voltage.



APPLICATION INFORMATION

TLV5639 interfaced to TMS320C203 DSP

hardware interface

Figure 13 shows an example of the connection between the TLV5639 and the TMS320C203 DSP. The only other device that is needed in addition to the DSP and the DAC is the 74AC138 address decoding circuit. Using this configuration, the DAC data is at address 0x0084 and the DAC control word is at address 0x0085 within the I/O memory space of the TMS320C203.

LDAC is tied low so that the output voltage is updated on the rising WE edge.

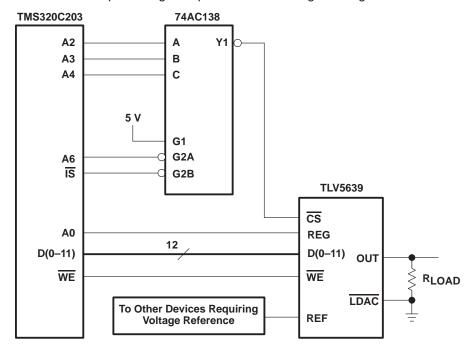


Figure 13. TLV5639 to TMS320C203 DSP Interface Connection

software

Writing data or control information to the TLV5639 is done using a single command. For example, the line of code which reads:

out 62h, dac_ctrl

writes the contents of address 0x0062 to the I/O address equated to dac_ctrl (0x0085, the address where the DAC control register has been mapped).

The following code shows how to set the DAC up to use the internal reference and operate in FAST mode by a write to the control register. Timer interrupts are then enabled and repeatedly generated every 205 μ s to provide a timebase for synchronizing the waveform generation. In this example, the waveform is generated by simply incrementing a counter and outputting the counter value to the DAC data word once every timer interrupt. This results in a saw waveform.



APPLICATION INFORMATION

```
; File:
             RAMP.ASM
; Function:
             ramp generation with TLV5639
; Processors: TMS320C203
; © 1999 Texas Instruments
;----- I/O and memory mapped regs -----
   .include "regs.asm"
dac_data .equ 0084h dac_ctrl .equ 0085h
;----- vectors -----
               0h
         .ps
         b
               start
         b
               INT1
         b
               INT23
         b
               TIM_ISR
 -----Main Program-----
         .ps
             1000h
         .entry
start:
         ldp
              #0
                    ; set data page to 0
; disable interrupts
         setc INTM
; disable maskable interrupts
         splk #0ffffh, IFR
         splk
               #0004h, IMR
; set up the timer
         splk #0000h, 60h
         splk #0042h, 61h
         out
               61h, PRD
               60h, TIM
         out
         splk #0c2fh, 6
out 62h, TCR
                        62h
         splk #0011h, 62h ; set up the DAC
; SPD=1 (FAST mode) and ; REF1=1 (2.048 V internal ref enable)
               62h, dac_ctrl
         out
         clrc
              INTM
                            ; enable interrupts
; loop forever!
        idle
next
b
         next
----- Interrupt Service Routines-----
INT1:
        ret
                     ; do nothing and return
INT23:
        ret
                    ; do nothing and return
TIM_ISR:
; timer interrupt handler
         add
              #1h
                    ; increment accumulator
               60h
         sacl
               60h, dac_data ; write to DAC
         out
                        ; re-enable interrupts
         clrc
              intm
                           ; return from interrupt
         ret
         .END
```

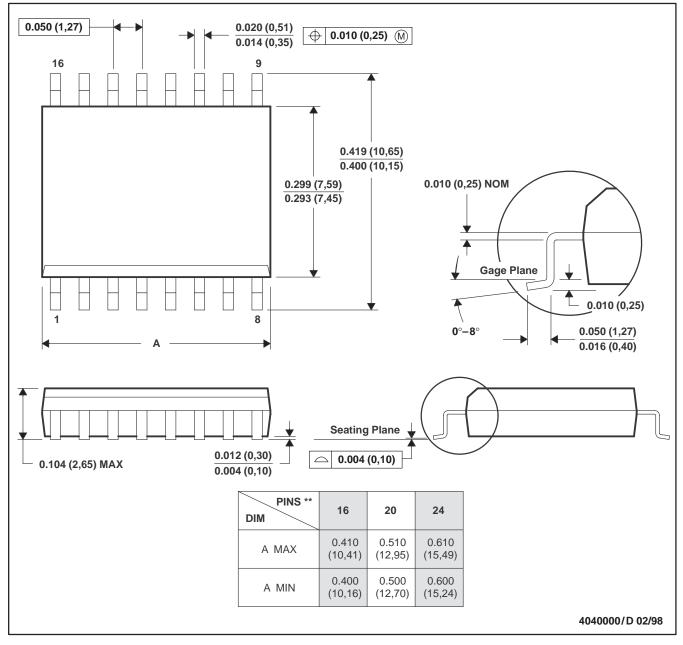


MECHANICAL DATA

DW (R-PDSO-G**)

16 PIN SHOWN

PLASTIC SMALL-OUTLINE PACKAGE



NOTES: A. All linear dimensions are in inches (millimeters).

- B. This drawing is subject to change without notice.
- C. Body dimensions do not include mold flash or protrusion not to exceed 0.006 (0,15).
- D. Falls within JEDEC MS-013

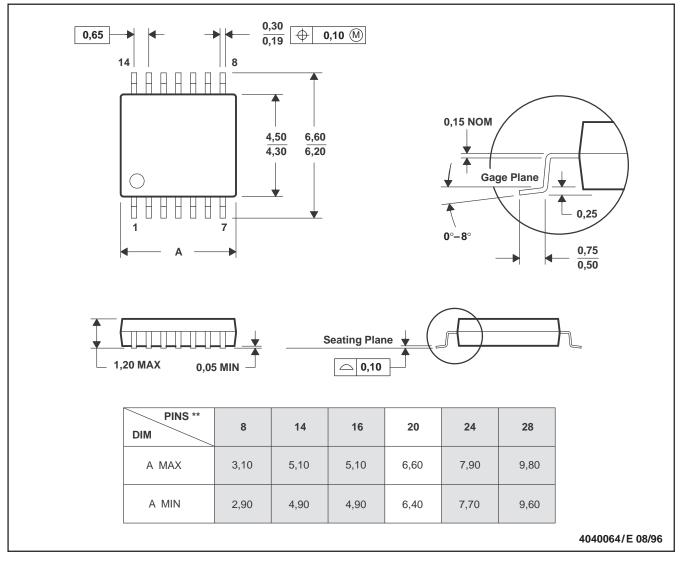


MECHANICAL DATA

PW (R-PDSO-G**)

14 PIN SHOWN

PLASTIC SMALL-OUTLINE PACKAGE



NOTES: A. All linear dimensions are in millimeters.

B. This drawing is subject to change without notice.

C. Body dimensions do not include mold flash or protrusion not to exceed 0,15.

D. Falls within JEDEC MO-153

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